Search Notes			

Application/Control No.	Applicant(s)/Patent un Reexamination	nder
10/618,536	LIN ET AL.	
Examiner	Art Unit	
Thien F. Tran	2811	

SEARCHED			
Class	Subclass	Date	Examiner
438	618, 622	4/29/2005	тт
438	625-627	4/29/2005	) тт
438	634, 637	4/29/2005	TT
438	639, 660	4/29/2005	тт
438	687	4/29/2005	TT
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
438	622, 687	4/29/2005	TT
438	625-627	4/29/2005	TT
438	634, 637	4/29/2005	тт
438/639, 660		4/29/2005	тт

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
		DATE	EXMR
EAS	т	4/29/2005	тт
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